

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>	Application No.	10/586,979	
	Filing Date	July 8, 2008	
	First Named Inventor	Steen Brummerstedt Iversen et al.	
	Art Unit	1796	
	Examiner	Chun Cheng Wang	
(Multiple sheets used when necessary)		Attorney Docket No.	PL.OUG17.003APC
SHEET 1 OF 1			

## U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
	1	US 2004/0110871 A1	06-10-2004	Michael Perrut et al.	

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T <sup>1</sup>
	2	FR 01 06403 A1	05-15-2001	Michel Perrut et al.		

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>1</sup>
	3	BEAUCAGE, G. et al., "Structural studies of complex systems using small-angle scattering: a unified Guinier/power-law approach" Journal of Non-Crystalline Solids, 1994, Pages 797-805, Vol. 172-174	

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Examiner Signature	/Chun-Cheng Wang/	Date Considered	06/25/2010
<p>*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>			

T<sup>1</sup> - Place a check mark in this area when an English language translation is attached.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /CCW/